

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination TOMONO ET AL.	
		Examiner David A. Zarneke	Art Unit 2827	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6028353	02-2000	Nakano et al.	257/701
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Takaya et al., US Patent Application Publication 2002/0009577 A1, 1/24/02.
	V	Kitamura, US Patent Application Publication 2002/0093415 A1, 7/18/02.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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